Agilent Technologies to Showcase Custom OFDM Waveform Design at 2010 Wireless Innovation Forum

SANTA CLARA, Calif. -- (BUSINESS WIRE) -- Agilent Technologies Inc. today announced that it will demonstrate the latest design and test innovations for software-defined radio (SDR) at the 2010 Wireless Innovation Forum, Dec. 1-2, in Washington, D.C. The demonstration will highlight Agilent's new design and verification tools for orthogonal frequency-division multiplexing (OFDM) technology, a family of high-performance communications formats.

"SDR developers require design and measurement tools that help them respond quickly in a dynamic marketplace," said Daren McClearnon, product marketing manager within Agilent Technologies' EEsof organization. "Our modular design tool approach enables custom OFDM measurements today and well into the future. This will help developers design new leading-edge and specialty waveforms, not just measure them."

Agilent's solution for SDR developers consists of a new custom OFDM design personality that runs on the SystemVue electronic system-level software platform. Agilent previously announced a custom OFDM measurement personality for its 89600B Vector Signal Analyzer software. The two software personalities interoperate, enabling system architects and verifiers to create consistent, custom formats for both simulation and measurement scenarios.

For more information on the OFDM capabilities demonstration, visit Agilent at the 2010 Wireless Innovation Forum, booth X and Y. You also may view a video demonstration or download the related SystemVue application note at:

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